

DMN3013LDG

# 30V SYNCHRONOUS N-CHANNEL ENHANCEMENT MODE MOSFET PowerDI3333-8 (Type D)

#### **Product Summary**

Device	BV <sub>DSS</sub>	R <sub>DS(ON)</sub> Max
Q1	30V	14.3m $\Omega$ @ V <sub>GS</sub> = 8V, I <sub>D</sub> = 4A
Q2	30V	14.3m $\Omega$ @ V <sub>GS</sub> = 8V, I <sub>D</sub> = 4A

#### **Features and Benefits**

- 100% Unclamped Inductive Switch (UIS) Test in Production
- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Lead-Free Finish; RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

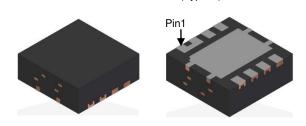
#### **Description and Applications**

This new generation MOSFET is designed to minimize the on-state resistance (R<sub>DS(ON)</sub>) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- DC-DC Converters
- Power Management Functions
- Analog Switch

#### **Mechanical Data**

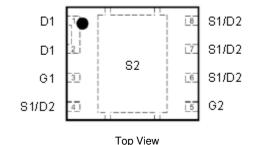
- Case: PowerDI<sup>®</sup>3333-8 (Type D)
- Case Material: Molded Plastic, "Green" Molding Compound.
   UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Matte Tin Annealed over Copper Leadframe.
   Solderable per MIL-STD-202, Method 208 <a>®</a>
- Weight: 0.044 grams (Approximate)



PowerDI3333-8 (Type D)

Top View

**Bottom View** 



Pin Configuration

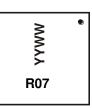
#### Ordering Information (Note 4)

Part Number	Case	Packaging
DMN3013LDG-7	PowerDI3333-8 (Type D)	1,000/Tape & Reel
DMN3013LDG-13	PowerDI3333-8 (Type D)	3,000/Tape & Reel

Notes:

- 1. EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant. All applicable RoHS exemptions applied.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/

#### **Marking Information**



R07 = Product Type Marking Code YYWW = Date Code Marking YY = Last Two Digits of Year (ex: 18 = 2018) WW = Week Code (01 to 53)



## **Maximum Ratings** (@ $T_A = +25^{\circ}C$ , unless otherwise specified.)

Characteristic	Symbol	Q1	Q2	Unit	
Drain-Source Voltage	$V_{DSS}$	30		V	
Gate-Source Voltage		$V_{GSS}$	10		V
Continuous Dusin Compant QV 5V	$T_C = +25$ °C $T_C = +70$ °C	l <sub>D</sub>	15 12		А
Continuous Drain Current @ V <sub>GS</sub> = 5V	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I <sub>D</sub>	9.5 7.6		А
Continuous Source-Drain Diode Current (Note 5)	Is	2.7	2.7	Α	
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)		I <sub>DM</sub>	80	80	Α
Avalanche Current (Note 6) L = 0.1mH		I <sub>AS</sub>	24	24	Α
Avalanche Energy (Note 6) L = 0.1mH		E <sub>AS</sub>	28	28	mJ

## Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Bower Dissination	$T_A = +25^{\circ}C$	ם	2.16	w
Total Power Dissipation	$T_A = +70$ °C	P <sub>D</sub>	1.25	VV
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	Б	58.8	
mermai nesistance, Junction to Ambient (Note 5)	t<10s	$R_{\theta JA}$	34	°C/W
Thermal Resistance, Junction to Case	$R_{\theta JC}$	6.9		
Operating and Storage Temperature Range	$T_{J}, T_{STG}$	-55 to +150	°C	

#### Electrical Characteristics Q1 (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1	μA	$V_{DS} = 20V, V_{GS} = 0V$
Gate-Source Leakage	IGSS	_	_	100	nA	$V_{GS} = 10V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	0.75	0.95	1.2	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
			10.9	14.3	mΩ	$V_{GS} = 8V$ , $I_D = 4A$
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	_	13.3	16.1	mΩ	$V_{GS} = 4.5V, I_D = 4A$
		_	15.3	17.7	mΩ	$V_{GS} = 3.5V, I_D = 4A$
Forward Transfer Admittance	Y <sub>FS</sub>		13	_	S	V <sub>DS</sub> = 15V, I <sub>D</sub> =4A
Diode Forward Voltage	V <sub>SD</sub>	_	0.8	1.0	V	$V_{GS} = 0V$ , $I_S = 4A$
DYNAMIC CHARACTERISTICS (Note 8)				•		
Input Capacitance	C <sub>iss</sub>	_	387	600		V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1.0MHz
Output Capacitance	Coss	_	219	350	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	10.4	16		
Gate Resistance	$R_{G}$	_	3.3	6.8	Ω	$V_{DS} = 0V, V_{GS} = 0V,$ f = 1.0MHz
Total Gate Charge (V <sub>GS</sub> = 4.5V)	$Q_{G}$	_	3.3	5.7		
Total Gate Charge at V <sub>TH</sub>	Q <sub>G(TH)</sub>		0.37	_	0	
Gate-Source Charge	Q <sub>GS</sub>		0.6	_	nC	$V_{DS} = 15V, I_{D} = 4A$
Gate-Drain Charge	$Q_{GD}$		0.6	_		
Turn-On Delay Time	t <sub>D(ON)</sub>		4.2	6.3		
Turn-On Rise Time	t <sub>R</sub>		6.2	_		$\begin{split} V_{DD} &= 15 V, \ V_{GS} = 4.5 V, \\ I_D &= 4 A, \ R_G = 2 \Omega \end{split}$
Turn-Off Delay Time	t <sub>D(OFF)</sub>		9.7	15	ns	
Turn-Off Fall Time	t <sub>F</sub>	_	2.0	_		
Reverse Recovery Time	t <sub>RR</sub>		11.7	_	ns	$V_{DS} = 15V, I_F = 4A,$
Reverse Recovery Charge	Q <sub>RR</sub>		7.5	_	nC	di/dt = 300A/µs

5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate. Notes:

<sup>6.</sup> I<sub>AS</sub> and E<sub>AS</sub> ratings are based on low frequency and duty cycles to keep T<sub>J</sub> = +25°C.
7. Short duration pulse test used to minimize self-heating effect.
8. Guaranteed by design. Not subject to product testing.

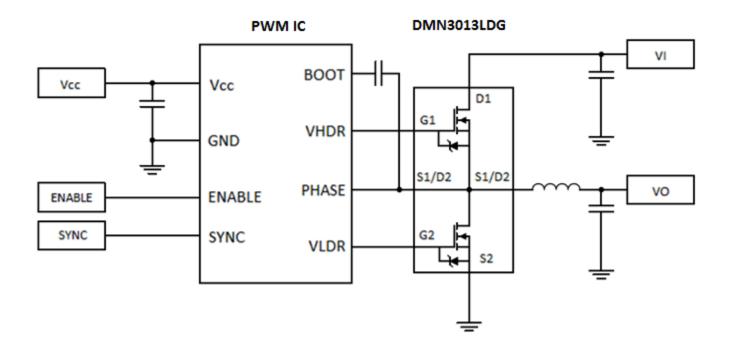


## Electrical Characteristics Q2 (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	$BV_{DSS}$	30	1	_	V	$V_{GS} = 0V$ , $I_D = 250 \mu A$
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	_		1.0	μΑ	$V_{DS} = 20V$ , $V_{GS} = 0V$
Gate-Source Leakage	I <sub>GSS</sub>	_	1	100	nA	$V_{GS} = 10V$ , $V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	0.75	0.95	1.2	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
		_	10.2	14.3	mΩ	$V_{GS} = 8V$ , $I_D = 4A$
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	_	12.7	16.1	mΩ	$V_{GS} = 4.5V, I_D = 4A$
		_	14.8	17.7	mΩ	$V_{GS} = 3.5V, I_D = 4A$
Forward Transfer Admittance	Y <sub>FS</sub>	_	13	_	S	$V_{DS} = 15V, I_{D} = 4A$
Diode Forward Voltage	$V_{SD}$	_	0.8	1.0	V	$V_{GS} = 0V$ , $I_S = 4A$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	Ciss	_	397	600	pF	V 15V V 0V
Output Capacitance	Coss	_	217	350	pF	$V_{DS} = 15V, V_{GS} = 0V,$ - f = 1.0MHz
Reverse Transfer Capacitance	Crss	_	10.4	16	pF	
Gate Resistance	Rg	_	3.3	6.8	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$
Total Gate Charge (V <sub>GS</sub> = 4.5V)	$Q_{G}$	_	3.4	5.7	nC	
Total Gate Charge at V <sub>TH</sub>	Q <sub>G(TH)</sub>	_	0.39	_	nC	Vns = 15V. In = 4A
Gate-Source Charge	Q <sub>GS</sub>	_	0.6	_	nC	V <sub>DS</sub> = 15V, I <sub>D</sub> = 4A
Gate-Drain Charge	Q <sub>GD</sub>	_	0.6	_	nC	
Turn-On Delay Time	t <sub>D(ON)</sub>	_	4.4	6.3	ns	
Turn-On Rise Time	t <sub>R</sub>	_	6.7	_	ns	$V_{DD} = 15V, V_{GS} = 4.5V,$
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	10.4	15	ns	$I_D = 4A$ , $R_G = 2\Omega$
Turn-Off Fall Time	t <sub>F</sub>	_	2.2	_	ns	
Reverse Recovery Time	t <sub>RR</sub>	_	11.8	_	ns	V 45V 1 4A 48/44 000A/
Reverse Recovery Charge	Q <sub>RR</sub>	_	7.8	_	nC	$V_{DS} = 15V$ , $I_F = 4A$ , $di/dt = 300A/\mu s$

7. Short duration pulse test used to minimize self-heating effect. 8. Guaranteed by design. Not subject to product testing. Notes:

## **Typical Circuit**





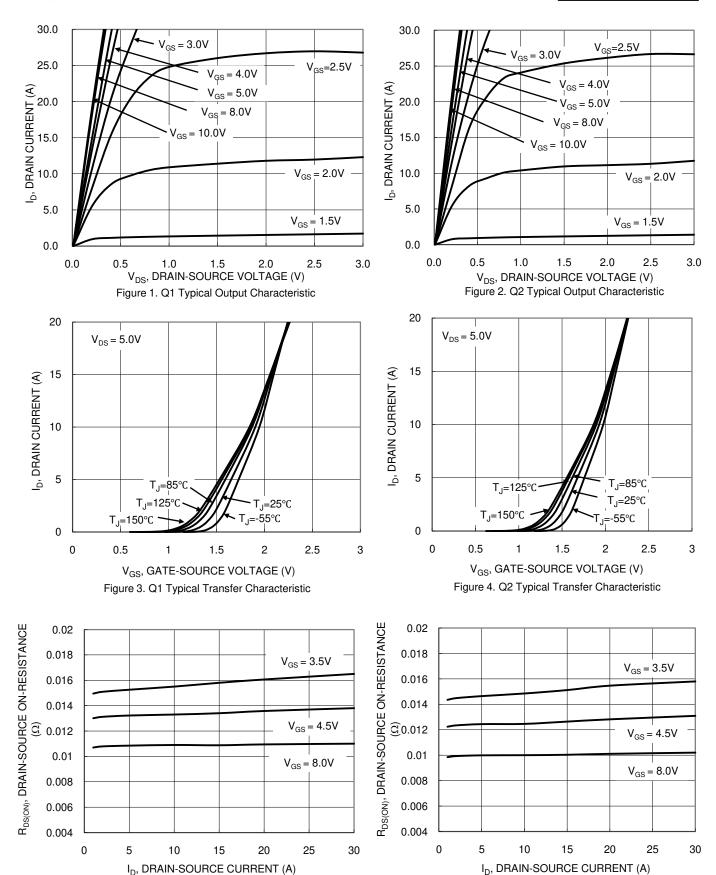
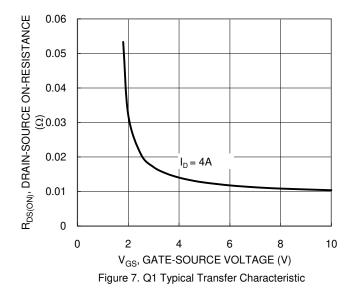
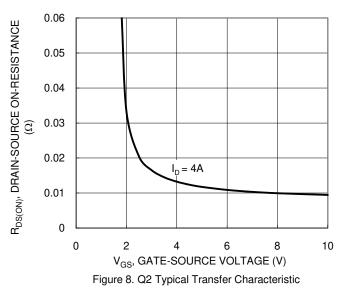
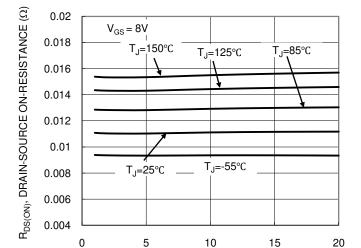


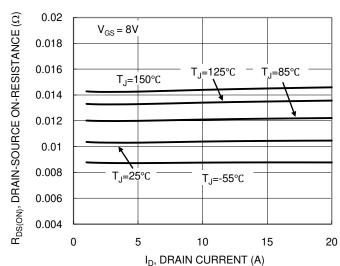
Figure 5. Q1 Typical On-Resistance vs. Drain Current and Gate Voltage Figure 6. Q2 Typical On-Resistance vs. Drain Current and Gate Voltage





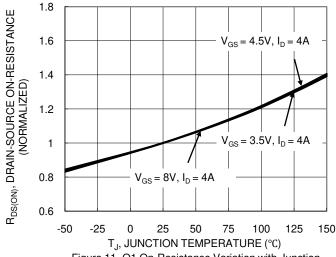






I<sub>D</sub>, DRAIN CURRENT (A)
Figure 9. Q1 Typical On-Resistance vs. Drain Current and Junction Temperature

Figure 10. Q2 Typical On-Resistance vs. Drain Current and Junction Temperature



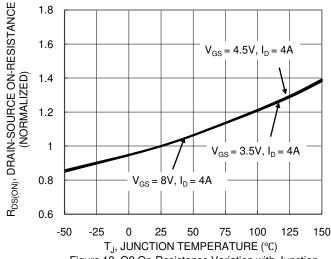
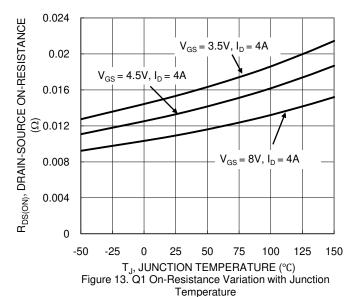
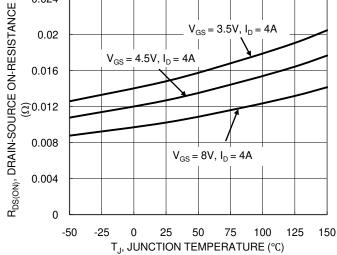


Figure 11. Q1 On-Resistance Variation with Junction Temperature

Figure 12. Q2 On-Resistance Variation with Junction Temperature







0.024

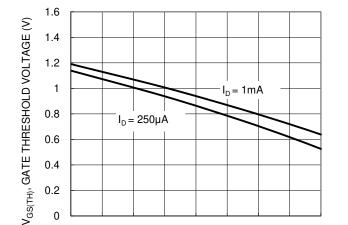


Figure 14. Q2 On-Resistance Variation with Junction Temperature

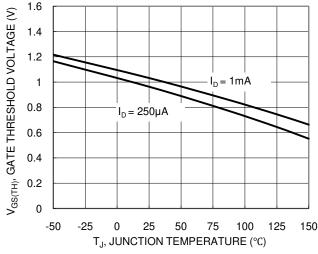


75

100

125

50



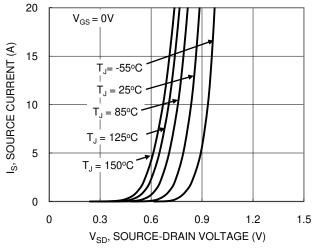
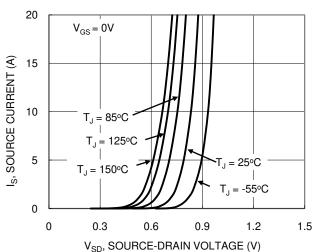


Figure 16. Q2 Gate Threshold Variation vs. Junction Temperature

Figure 17. Q1 Diode Forward Voltage vs. Current

Figure 18. Q2 Diode Forward Voltage vs. Current



-50

-25

0

25



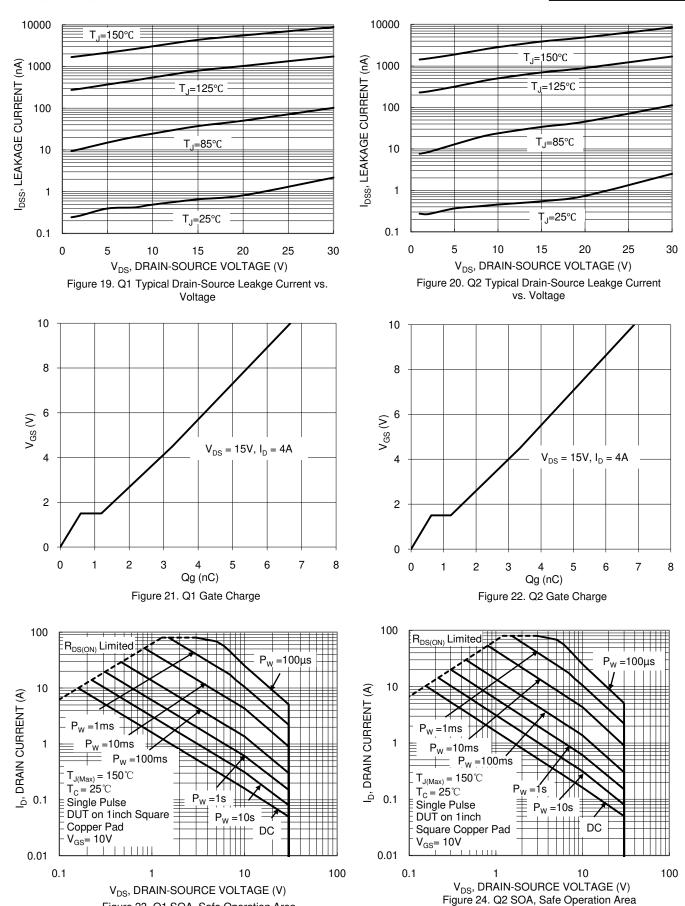


Figure 23. Q1 SOA, Safe Operation Area



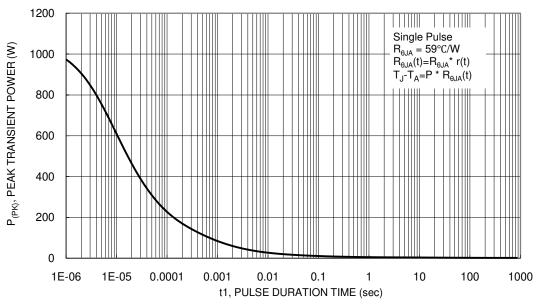


Figure 25. Single Pulse Maximum Power Dissipation

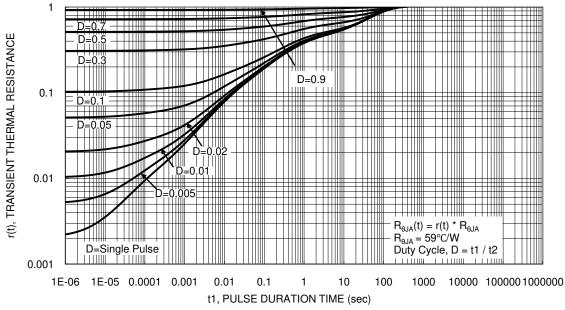


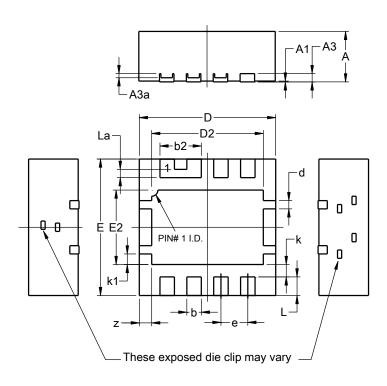
Figure 26. Transient Thermal Resistance



#### **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### PowerDI3333-8 (Type D)

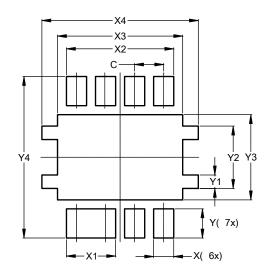


PowerDI3333-8						
(Type D)						
Dim	Min	Max	Тур			
Α	1.17	1.23	1.20			
<b>A</b> 1	0.00	0.05	0.02			
А3	0.15	0.25	0.20			
A3a	0.05	0.15	0.10			
b	0.30	0.40	0.35			
b2	0.95	1.05	1.00			
D	3.20	3.40	3.30			
D2	2.65	2.75	2.70			
Е	3.20	3.40	3.30			
E2	1.75	1.85	1.80			
d	0.15	0.25	0.20			
e	-		0.65			
k	-		0.30			
k1	0.21	0.31	0.26			
٦	0.40	0.50	0.45			
La	0.15	0.25	0.20			
Z	0.25	0.35	0.30			
All Dimensions in mm						

#### **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### PowerDI3333-8 (Type D)



Dimensions	Value (in mm)			
С	0.650			
X	0.450			
X1	1.100			
X2	2.400			
Х3	2.800			
X4	3.500			
Υ	0.650			
Y1	0.300			
Y2	1.390			
Y3	1.900			
Y4	3.600			



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